

**Notice of References Cited**

 Application/Control No.  
 10/635,649

 Applicant(s)/Patent Under  
 Reexamination  
 HATADE ET AL.

 Examiner  
 VAN T. PHAM

 Art Unit  
 2627

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,728,193	04-2004	Uchizaki et al.	369/112.01
*	B	US-2001/0000310	04-2001	Yoo et al.	369/112.26
*	C	US-7,075,880	07-2006	Honda et al.	369/112.08
*	D	US-6,118,749	09-2000	Arai et al.	369/112.26
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2001-348367 <i>translation</i>	12-2000	Japan	Yamamiya Kunio	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.